

Articles

1. Overney, F., Pimsut, Y., Bauer, S., Kieler, O., Behr, R. & Jeanneret, B.
Load compensation bridge for Josephson arbitrary waveform synthesizers.
Measurement Science and Technology **31**, 055004. ISSN: 0957-0233. doi:[10.1088/1361-6501/ab62c7](https://doi.org/10.1088/1361-6501/ab62c7) (2020).
2. Corminboeuf, D.
Calibration of the Absolute Linearity of Lock-In Amplifiers.
IEEE Transactions on Instrumentation and Measurement **68**, 2060–2065. ISSN: 0018-9456. doi:[10.1109/TIM.2018.2881808](https://doi.org/10.1109/TIM.2018.2881808) (2019).
3. Gournay, P., Rolland, B., Chayramy, R., Overney, F., Yang, Y., Huang, L., Lu, Z., Wang, Y., Koffman, A., Johnson, L., Xie, R., Belliss, J., Giblin, S., Thornton, B., Schurr, J., Lee, J. & Semenov, Y.
Comparison CCEM-K4.2017 of 10 pF and 100 pF capacitance standards.
Metrologia **56**, 01001–01001. ISSN: 0026-1394. doi:[10.1088/0026-1394/56/1A/01001](https://doi.org/10.1088/0026-1394/56/1A/01001) (2019).
4. Overney, F. & Jeanneret, B.
Impedance bridges: from Wheatstone to Josephson.
Metrologia **55**, S119–S134. ISSN: 0026-1394. doi:[10.1088/1681-7575/aacf6c](https://doi.org/10.1088/1681-7575/aacf6c) (2018).
5. Ortolano, M., Palafox, L., Kučera, J., Callegaro, L., D’Elia, V., Marzano, M., Overney, F., Gülmez, G., Kucera, J., Callegaro, L., D’Elia, V., Marzano, M., Overney, F. & Gülmez, G.
An international comparison of phase angle standards between the novel impedance bridges of CMI, INRIM and METAS.
Metrologia **55**, 499–512. ISSN: 0026-1394. doi:[10.1088/1681-7575/aabf24](https://doi.org/10.1088/1681-7575/aabf24) (2018).
6. Gournay, P., Rolland, B., Mortara, A. & Jeanneret, B.
On-site comparison of Quantum Hall Effect resistance standards of METAS and the BIPM: Ongoing key comparison BIPM.EM-K12.
Metrologia **55**, 01002–01002. ISSN: 0026-1394. doi:[10.1088/0026-1394/55/1A/01002](https://doi.org/10.1088/0026-1394/55/1A/01002) (2018).
7. Agustoni, M. & Mortara, A.
A Calibration Setup for IEC 61850-9-2 Devices.
IEEE Transactions on Instrumentation and Measurement **66**, 1124–1130. ISSN: 0018-9456. doi:[10.1109/TIM.2017.2665938](https://doi.org/10.1109/TIM.2017.2665938) (2017).
8. Overney, F. & Jeanneret, B.
Calibration of an LCR-Meter at Arbitrary Phase Angles Using a Fully Automated Impedance Simulator.
IEEE Transactions on Instrumentation and Measurement **66**, 1516–1523. ISSN: 0018-9456. doi:[10.1109/TIM.2017.2652500](https://doi.org/10.1109/TIM.2017.2652500) (2017).
9. Luond, F., Kalmbach, C.-C., Overney, F., Schurr, J., Jeanneret, B., Muller, A., Kruskopf, M., Pierz, K. & Ahlers, F.
AC Quantum Hall Effect in Epitaxial Graphene.
IEEE Transactions on Instrumentation and Measurement **66**, 1459–1466. ISSN: 0018-9456. doi:[10.1109/TIM.2017.2652501](https://doi.org/10.1109/TIM.2017.2652501) (2017).
10. Thodkar, K., Thompson, D., Lüönd, F., Moser, L., Overney, F., Marot, L., Schönenberger, C., Jeanneret, B. & Calame, M.
Restoring the Electrical Properties of CVD Graphene via Physisorption of Molecular Adsorbates.
ACS Applied Materials and Interfaces **9**, 25014–25022. doi:[10.1021/acsami.7b05143](https://doi.org/10.1021/acsami.7b05143) (2017).
11. Schurr, J., Fletcher, N., Gournay, P., Thévenot, O., Overney, F., Johnson, L., Xie, R. & Dierikx, E.
Final report of the supplementary comparison EURAMET.EM-S31 comparison of capacitance and capacitance ratio.
Metrologia **54**, 01016–01016. ISSN: 0026-1394. doi:[10.1088/0026-1394/54/1A/01016](https://doi.org/10.1088/0026-1394/54/1A/01016) (2017).
12. Mohns, E., Mortara, A., Cayci, H., Houtzager, E., Fricke, S., Agustoni, M. & Ayhan, B. **Calibration of Commercial Test Sets for Non-Conventional Instrument Transformers.** in *2017 IEEE International Workshop on Applied Measurements for Power Systems (AMPS)* (IEEE, 2017), 1–6. ISBN: 978-1-5386-0343-7. doi:[10.1109/AMPS.2017.8078324](https://doi.org/10.1109/AMPS.2017.8078324).
13. Overney, F., Flowers-Jacobs, N. E., Jeanneret, B., Rüfenacht, A., Fox, A. E., Underwood, J. M., Koffman, A. D. & Benz, S. P.
Josephson-based full digital bridge for high-accuracy impedance comparisons.
Metrologia **53**, 1045–1053. ISSN: 0026-1394. doi:[10.1088/0026-1394/53/4/1045](https://doi.org/10.1088/0026-1394/53/4/1045) (2016).

14. Overney, F., Lüönd, F. & Jeanneret, B.
Broadband fully automated digitally assisted coaxial bridge for high accuracy impedance ratio measurements.
Metrologia **53**, 918–926. ISSN: 0026-1394. doi:[10.1088/0026-1394/53/3/918](https://doi.org/10.1088/0026-1394/53/3/918) (2016).
15. Thodkar, K., El Abbassi, M., Lüönd, F., Overney, F., Schönenberger, C., Jeanneret, B. & Calame, M.
Comparative study of single and multi domain CVD graphene using large-area Raman mapping and electrical transport characterization.
physica status solidi (RRL) - Rapid Research Letters **10**, 807–811. ISSN: 18626254. doi:[10.1002/pssr.201600211](https://doi.org/10.1002/pssr.201600211) (2016).
16. Zhao, D., Rietveld, G., Braun, J.-P., Overney, F., Lippert, T. & Christensen, A.
Traceable measurements of the electrical parameters of solid-state lighting products.
Metrologia **53**, 1384–1394. ISSN: 0026-1394. doi:[10.1088/0026-1394/53/6/1384](https://doi.org/10.1088/0026-1394/53/6/1384) (2016).
17. Corminboeuf, D. & Overney, F.
Inductive voltage divider calibration with sampling method.
EPJ Web of Conferences **77** (eds Filtz, J.-R., Larquier, B., Claudel, P. & Favreau, J.-O.) 00014. ISSN: 2100-014X. doi:[10.1051/epjconf/20147700014](https://doi.org/10.1051/epjconf/20147700014) (2014).
18. Overney, F. & Mortara, A.
Synchronization of Sampling-Based Measuring Systems.
IEEE Transactions on Instrumentation and Measurement **63**, 89–95. ISSN: 0018-9456. doi:[10.1109/TIM.2013.2275204](https://doi.org/10.1109/TIM.2013.2275204) (2014).
19. Jeckelmann, B., van der Beek, J. H. N., Capra, P. P., Chrobok, P., Cirneanu, L., Dudek, E., Erkan, Ö., Flouda, I., Galliana, F., Godinho, I., Gunnarsson, O., Iisakka, I., Istrate, D., Lindic, M., Nicolas, J., Orzepowski, M., Pezel, A., Raso, F., Rietveld, G., Schumacher, B., Snopek, L., Tenev, A. & Vrabcek, P.
Final report on supplementary comparison EURAMET.EM-S32: Comparison of resistance standards at 1 TΩ and 100 TΩ.
Metrologia **50**, 01008–01008. ISSN: 1681-7575. doi:[10.1088/0026-1394/50/1A/01008](https://doi.org/10.1088/0026-1394/50/1A/01008) (2013).
20. Jeckelmann, B., Abdel Aziz, H. S., Dudek, E., Ilic, D., Lenicek, I., Tadros, N. N., Orzepowski, M. & Tenev, A.
RMO key comparison EURAMET.EM-K2.1: Comparison of resistance standards at 10 MΩ and 1 GΩ.
Metrologia **50**, 01001–01001. ISSN: 1681-7575. doi:[10.1088/0026-1394/50/1A/01001](https://doi.org/10.1088/0026-1394/50/1A/01001) (2013).
21. Rietveld, G., van der Beek, J. H. N., Kraft, M., Elmquist, R. E., Mortara, A. & Jeckelmann, B.
Low-Ohmic Resistance Comparison: Measurement Capabilities and Resistor Traveling Behavior.
IEEE Transactions on Instrumentation and Measurement **62**, 1723–1728. ISSN: 0018-9456. doi:[10.1109/TIM.2012.2225917](https://doi.org/10.1109/TIM.2012.2225917) (2013).
22. Jeanneret, B., Overney, F. & Rüfenacht, A.
The Josephson locked synthesizer.
Measurement Science and Technology **23**, 124004. ISSN: 0957-0233. doi:[10.1088/0957-0233/23/12/124004](https://doi.org/10.1088/0957-0233/23/12/124004) (2012).
23. Solve, S., Chayramy, R., Stock, M. & Jeanneret, B.
Comparison of the Josephson voltage standards of the METAS and the BIPM (part of the ongoing BIPM key comparison BIPM.EM-K10.a and b).
Metrologia **49**, 01010–01010. ISSN: 0026-1394. doi:[10.1088/0026-1394/49/1A/01010](https://doi.org/10.1088/0026-1394/49/1A/01010) (2012).
24. Eichenberger, A., Baumann, H., Jeanneret, B., Jeckelmann, B., Richard, P. & Beer, W.
Determination of the Planck constant with the METAS watt balance.
Metrologia **48**, 133–141. ISSN: 0026-1394. doi:[10.1088/0026-1394/48/3/007](https://doi.org/10.1088/0026-1394/48/3/007) (2011).
25. Rüfenacht, A., Overney, F., Mortara, A., Jeanneret, B., Rüfenacht, A., Overney, F., Mortara, A. & Jeanneret, B.
Thermal-Transfer Standard Validation of the Josephson-Voltage-Standard-Locked Sine-Wave Synthesizer.
IEEE Transactions on Instrumentation and Measurement **60**, 2372–2377. ISSN: 0018-9456. doi:[10.1109/TIM.2010.2099931](https://doi.org/10.1109/TIM.2010.2099931) (2011).
26. Jeanneret, B., Rüfenacht, A., Overney, F., van den Brom, H. & Houtzager, E.
High precision comparison between a programmable and a pulse-driven Josephson voltage standard.
Metrologia **48**, 311–316. ISSN: 0026-1394. doi:[10.1088/0026-1394/48/5/011](https://doi.org/10.1088/0026-1394/48/5/011) (2011).

27. Overney, F. & Jeanneret, B.
RLC Bridge Based on an Automated Synchronous Sampling System.
IEEE Transactions on Instrumentation and Measurement **60**, 2393–2398. ISSN: 0018-9456. doi:[10.1109/TIM.2010.2100650](https://doi.org/10.1109/TIM.2010.2100650) (2011).
28. Overney, F., Rufenacht, A., Braun, J.-P., Jeanneret, B. & Wright, P. S.
Characterization of Metrological Grade Analog-to-Digital Converters Using a Programmable Josephson Voltage Standard.
IEEE Transactions on Instrumentation and Measurement **60**, 2172–2177. ISSN: 0018-9456. doi:[10.1109/TIM.2011.2113950](https://doi.org/10.1109/TIM.2011.2113950) (2011).
29. Overney, F. & Jeanneret, B.
Realization of an inductance scale traceable to the quantum Hall effect using an automated synchronous sampling system.
Metrologia **47**, 690–698. ISSN: 0026-1394. doi:[10.1088/0026-1394/47/6/008](https://doi.org/10.1088/0026-1394/47/6/008) (2010).
30. Jeanneret, B., Overney, F., Rufenacht, A. & Nissila, J.
Strong Attenuation of the Transients' Effect in Square Waves Synthesized With a Programmable Josephson Voltage Standard.
IEEE Transactions on Instrumentation and Measurement **59**, 1894–1899. ISSN: 0018-9456. doi:[10.1109/TIM.2009.2030920](https://doi.org/10.1109/TIM.2009.2030920) (2010).
31. Jeckelmann, B. & Zeier, M.
Final report on RMO key comparison EUROMET.EM-K2: Comparison of resistance standards at 10 M Ω and 1 G Ω .
Metrologia **47**, 01006–01006. ISSN: 1681-7575. doi:[10.1088/0026-1394/47/1A/01006](https://doi.org/10.1088/0026-1394/47/1A/01006) (2010).
32. Jeanneret, B. & Benz, S. P.
Application of the Josephson effect in electrical metrology.
The European Physical Journal Special Topics **172**, 181–206. ISSN: 1951-6355. doi:[10.1140/epjst/e2009-01050-6](https://doi.org/10.1140/epjst/e2009-01050-6) (2009).
33. Jeanneret, B., Overney, F., Callegaro, L., Mortara, A. & Rufenacht, A.
Josephson-Voltage-Standard-Locked Sine Wave Synthesizer: Margin Evaluation and Stability.
IEEE Transactions on Instrumentation and Measurement **58**, 791–796. ISSN: 0018-9456. doi:[10.1109/TIM.2008.2006963](https://doi.org/10.1109/TIM.2008.2006963) (2009).
34. Eichenberger, a., Genevès, G. & Gournay, P.
Determination of the Planck constant by means of a watt balance.
The European Physical Journal Special Topics **172**, 363–383. ISSN: 1951-6355. doi:[10.1140/epjst/e2009-01061-3](https://doi.org/10.1140/epjst/e2009-01061-3) (2009).
35. Ahlers, F. J., Jeanneret, B., Overney, F., Schurr, J. & Wood, B. M.
Compendium for precise ac measurements of the quantum {H}all resistance.
Metrologia **46**, R1–R11. ISSN: 0026-1394. doi:[10.1088/0026-1394/46/5/R01](https://doi.org/10.1088/0026-1394/46/5/R01) (2009).
36. Piquemal, F. & Jeckelmann, B.
Editorial.
The European Physical Journal Special Topics **172**, 1–4. ISSN: 1951-6355. doi:[10.1140/epjst/e2009-01037-3](https://doi.org/10.1140/epjst/e2009-01037-3) (2009).
37. Zimmerman, N. M., Huber, W. H., Simonds, B., Hourdakakis, E., Fujiwara, A., Ono, Y., Takahashi, Y., Inokawa, H., Furlan, M. & Keller, M. W.
Why the long-term charge offset drift in Si single-electron tunneling transistors is much smaller (better) than in metal-based ones: Two-level fluctuator stability.
Journal of Applied Physics **104**, 033710. ISSN: 0021-8979. doi:[10.1063/1.2949700](https://doi.org/10.1063/1.2949700) (2008).
38. Jeanneret, B. & Overney, F.
Phenomenological Model for Frequency-Related Dissipation in the Quantized Hall Resistance.
IEEE Transactions on Instrumentation and Measurement **56**, 431–434. ISSN: 0018-9456. doi:[10.1109/TIM.2007.891162](https://doi.org/10.1109/TIM.2007.891162) (2007).
39. Overney, F., Jeanneret, B., Jeckelmann, B., Wood, B. M. B. & Schurr, J.
The quantized Hall resistance: towards a primary standard of impedance.
Metrologia **43**, 409–413. ISSN: 0026-1394. doi:[10.1088/0026-1394/43/5/011](https://doi.org/10.1088/0026-1394/43/5/011) (2006).

40. Schurr, J., Ahlers, F. J. F.-J., Hein, G., Melcher, J., Pierz, K., Overney, F. & Wood, B. M. B.
AC longitudinal and contact resistance measurements of quantum Hall devices.
Metrologia **43**, 163–173. ISSN: 0026-1394. doi:[10.1088/0026-1394/43/1/021](https://doi.org/10.1088/0026-1394/43/1/021) (2006).
41. Hof, C., Jeanneret, B., Eichenberger, A., Overney, F., Keller, M. & Dalberth, M.
Manipulating Single Electrons With a Seven-Junction Pump.
IEEE Transactions on Instrumentation and Measurement **54**, 670–672. ISSN: 0018-9456. doi:[10.1109/TIM.2004.843066](https://doi.org/10.1109/TIM.2004.843066) (2005).
42. Overney, F., Jeanneret, B., Wood, B. & Schurr, J.
Influence of the Dissipation in AC Measurements of the Quantized Hall Resistance.
IEEE Transactions on Instrumentation and Measurement **54**, 658–661. ISSN: 0018-9456. doi:[10.1109/TIM.2004.843125](https://doi.org/10.1109/TIM.2004.843125) (2005).
43. Overney, F., Jeanneret, B., Wood, B. M. & Schurr, J.
Influence of the Dissipation in AC Measurements of the Quantized $\{H\}$ all Resistance.
IEEE Transactions on Instrumentation and Measurement **54**, 658–661. ISSN: 0018-9456. doi:[10.1109/TIM.2004.843125](https://doi.org/10.1109/TIM.2004.843125) (2005).
44. Marullo-Reedtz, G., Cerri, R., Waldmann, W., Streit, J., Immonen, P., Blanc, I., Raso, F., Funck, T., Schumacher, B., Dierikx, E., Nunes, M., Vrabcek, P., Rudohradsky, D., Gunnarsson, O., Rydler, K.-E., Jeanneret, B., Jeckelmann, B., Pulfer, T., Turhan, S., Yilmaz, O., Williams, J., Slinde, H., Lind, K., Nicolas, J., Lindic, M., Flouda, E. & Erdos, G.
Comparison EUROMET.EM-K8 of DC Voltage Ratio: Results.
IEEE Transactions on Instrumentation and Measurement **54**, 576–579. ISSN: 0018-9456. doi:[10.1109/TIM.2004.843481](https://doi.org/10.1109/TIM.2004.843481) (2005).
45. Schurr, J., Wood, B. & Overney, F.
Linear Frequency Dependence in AC Resistance Measurement.
IEEE Transactions on Instrumentation and Measurement **54**, 512–515. ISSN: 0018-9456. doi:[10.1109/TIM.2005.843583](https://doi.org/10.1109/TIM.2005.843583) (2005).
46. Jeckelmann, B. & Niederhauser, J.
Auf dem Weg zu einer Neudefinition des Kilogramms.
Pipette, Swiss Laboratory Medecine **2**, 8–11 (2004).
47. Schwitz, W., Jeckelmann, B. & Richard, P.
Towards a new kilogram definition based on a fundamental constant.
Comptes Rendus Physique **5**, 881–892. ISSN: 16310705. doi:[10.1016/j.crhy.2004.05.005](https://doi.org/10.1016/j.crhy.2004.05.005) (2004).
48. Eichenberger, A., Jeckelmann, B. & Richard, P.
Tracing Planck's constant to the kilogram by electromechanical methods.
Metrologia **40**, 356–365. ISSN: 0026-1394. doi:[10.1088/0026-1394/40/6/007](https://doi.org/10.1088/0026-1394/40/6/007) (2003).
49. Hof, C., Jeanneret, B., Eichenberger, A., Overney, F. & Lotkhov, S.
First steps toward a quantum capacitance standard at metas.
IEEE Transactions on Instrumentation and Measurement **52**, 604–607. ISSN: 0018-9456. doi:[10.1109/TIM.2003.810035](https://doi.org/10.1109/TIM.2003.810035) (2003).
50. Jeckelmann, B. & Jeanneret, B.
The quantum Hall effect as an electrical resistance standard.
Measurement Science and Technology **14**, 1229–1236. doi:[10.1088/0957-0233/14/8/306](https://doi.org/10.1088/0957-0233/14/8/306) (2003).
51. Overney, F., Jeanneret, B. & Jeckelmann, B.
Effects of metallic gates on ac measurements of the quantum hall resistance.
IEEE Transactions on Instrumentation and Measurement **52**, 574–578. ISSN: 0018-9456. doi:[10.1109/TIM.2003.810020](https://doi.org/10.1109/TIM.2003.810020) (2003).
52. Furlan, M. & Lotkhov, S. V.
Electrometry on charge traps with a single-electron transistor.
Physical Review B **67**, 205313. ISSN: 0163-1829. doi:[10.1103/PhysRevB.67.205313](https://doi.org/10.1103/PhysRevB.67.205313) (2003).
53. Beer, W., Eichenberger, A., Jeanneret, B., Jeckelmann, B., Pourzand, A., Richard, P. & Schwarz, J.
Status of the METAS watt balance experiment.
IEEE Transactions on Instrumentation and Measurement **52**, 626–630. ISSN: 0018-9456. doi:[10.1109/TIM.2003.810033](https://doi.org/10.1109/TIM.2003.810033) (2003).

54. Melcher, J., Schurr, J., Pierz, K., Williams, J., Giblin, S., Cabiati, F., Callegaro, L., Marullo-Reedtz, G., Cassiogo, C., Jeckelmann, B., Jeanneret, B., Overney, F., Bohacek, J., Riha, J., Power, O., Murray, J., Nunes, M., Lobo, M. & Godinho, I.
The european acqhe project: modular system for the calibration of capacitance standards based on the quantum hall effect.
IEEE Transactions on Instrumentation and Measurement **52**, 563–568. ISSN: 0018-9456. doi:[10.1109/TIM.2003.810731](https://doi.org/10.1109/TIM.2003.810731) (2003).
55. Van den Brom, H., Kerkhof, O., Lotkhov, S., Bogoslovsky, S. S., Willenberg, G.-D., Scherer, H., Zorin, A., Pedersen, S., Kristoffersson, C., Aassime, A., Delsing, P., Taslakov, M., Ivanov, Z., Nilsson, H., Giblin, S., Kleinschmidt, P., Hof, C., Eichenberger, A., Overney, F., Jeanneret, B., Genevis, G., Feltin, N., Devoille, L., Gay, F. & Piquemal, F.
Counting electrons one by one overview of a joint european research project.
IEEE Transactions on Instrumentation and Measurement **52**, 584–589. ISSN: 0018-9456. doi:[10.1109/TIM.2003.810736](https://doi.org/10.1109/TIM.2003.810736) (2003).
56. Behr, R., Kohlmann, J., Janssen, J. J. J.-T. J., Kleinschmidt, P., Williams, J., Djordjevic, S., Lo-Hive, J.-P., Piquemal, F., Hetland, P. P.-O., Reymann, D., Eklund, G., Hof, C., Jeanneret, B., Chevtchenko, O., Houtzager, E., van den Brom, H., Sosso, A., Andreone, D., Nissila, J., Helist, P., Nissilä, J., Helistö, P., Eklund, G., Hof, C., Jeanneret, B., Chevtchenko, O., Houtzager, E., van den Brom, H., Sosso, A., Andreone, D., Nissila, J., Helist, P., Penttila, J. & Helisto, P.
Analysis of different measurement setups for a programmable josephson voltage standard.
IEEE Transactions on Instrumentation and Measurement **52**, 524–528. ISSN: 0018-9456. doi:[10.1109/TIM.2003.811570](https://doi.org/10.1109/TIM.2003.811570) (2003).
57. Delahaye, F. & Jeckelmann, B.
Revised technical guidelines for reliable dc measurements of the quantized Hall resistance.
Metrologia **40**, 217–223. ISSN: 0026-1394. doi:[10.1088/0026-1394/40/5/302](https://doi.org/10.1088/0026-1394/40/5/302) (2003).
58. Jeckelmann, B. & Jeanneret, B.
The quantum $\{H\}$ all effect as an electrical resistance standard.
Reports on Progress in Physics **64**, 1603–1655. ISSN: 0034-4885. doi:[10.1088/0034-4885/64/12/201](https://doi.org/10.1088/0034-4885/64/12/201) (2001).
59. Jeckelmann, B., Rufenacht, A., Jeanneret, B., Overney, F., Pierz, K., von Campenhausen, A. & Hein, G.
Optimization of QHE-devices for metrological applications.
IEEE Transactions on Instrumentation and Measurement **50**, 218–222. ISSN: 00189456. doi:[10.1109/19.918106](https://doi.org/10.1109/19.918106) (2001).
60. Jeanneret, B., Rufenacht, A. & Burroughs, C.
High precision comparison between SNS and SIS Josephson voltage standards.
IEEE Transactions on Instrumentation and Measurement **50**, 188–191. ISSN: 00189456. doi:[10.1109/19.918098](https://doi.org/10.1109/19.918098) (2001).
61. Beer, W., Eichenberger, A., Jeanneret, B., Jeckelmann, B., Richard, P., Schneiter, H., Pourzand, A., Courteville, A., Dändliker, R., Schneiter, P., Pourzand, A., Courteville, A. & Dandliker, R.
The OFMET Watt balance: Progress report.
IEEE Transactions on Instrumentation and Measurement **50**, 583–586. ISSN: 00189456. doi:[10.1109/19.918197](https://doi.org/10.1109/19.918197) (2001).
62. Reymann, D., Witt, T., Vrabčėk, P., Tang, Y.-H., Hamilton, C., Katkov, A., Jeanneret, B. & Power, O.
Recent developments in BIPM voltage standard comparisons.
IEEE Transactions on Instrumentation and Measurement **50**, 206–209. doi:[10.1109/19.918103](https://doi.org/10.1109/19.918103) (2001).
63. Müller, H.-O., Furlan, M., Heinzl, T. & Ensslin, K.
Modelling background charge rearrangements near single-electron transistors as a Poisson process.
Europhysics Letters (EPL) **55**, 253–259. ISSN: 0295-5075. doi:[10.1209/epl/i2001-00407-y](https://doi.org/10.1209/epl/i2001-00407-y) (2001).
64. Furlan, M., Heinzl, T., Jeanneret, B. & Lotkhov, S.
Coulomb Blockade Peak Statistics Influenced by Background Charge Configuration.
Journal of Low Temperature Physics **118**, 297–306. doi:[10.1023/A:1004677514104](https://doi.org/10.1023/A:1004677514104) (2000).
65. Furlan, M., Heinzl, T., Jeanneret, B., Lotkhov, S. V. & Ensslin, K.
Non-Gaussian distribution of nearest-neighbour Coulomb peak spacings in metallic single-electron transistors.
Europhysics Letters (EPL) **49**, 369–375. ISSN: 0295-5075. doi:[10.1209/epl/i2000-00158-3](https://doi.org/10.1209/epl/i2000-00158-3) (2000).

66. Furlan, M., Eichenberger, A., Heinzel, T., Jeanneret, B. & Lotkhov, S.
Realistic and relevant models for the description of SET transistors.
Physica B: Condensed Matter **284-288**, 1798–1799. ISSN: 09214526. doi:[10.1016/S0921-4526\(99\)02988-9](https://doi.org/10.1016/S0921-4526(99)02988-9) (2000).
67. Overney, F., Jeanneret, B. & Furlan, M.
A tunable vacuum-gap cryogenic coaxial capacitor.
IEEE Transactions on Instrumentation and Measurement **49**, 1326–1330. ISSN: 00189456. doi:[10.1109/19.893278](https://doi.org/10.1109/19.893278) (2000).
68. Jeanneret, B. & Jeckelmann, B.
Comments on "Influence of voltage contacts on precision measurements of the quantized Hall resistance: an effect of externally injected current".
IEEE Transactions on Instrumentation and Measurement **48**, 1010. ISSN: 0018-9456. doi:[10.1109/19.799663](https://doi.org/10.1109/19.799663) (1999).
69. Beer, W., Jeanneret, B., Jeckelmann, B., Richard, P., Courteville, A., Salvadé, Y. & Dändliker, R.
A proposal for a new moving-coil experiment.
IEEE Transactions on Instrumentation and Measurement **48**, 192–195. doi:[10.1109/19.769561](https://doi.org/10.1109/19.769561) (1999).
70. Jeanneret, B., Jeckelmann, B. & Hall, B.
Contactless measurements of the internal capacitance of a Corbino ring in the quantum Hall regime.
IEEE Transactions on Instrumentation and Measurement **48**, 301–304. ISSN: 00189456. doi:[10.1109/19.769588](https://doi.org/10.1109/19.769588) (1999).
71. Furlan, M.
Electronic transport and the localization length in the quantum Hall effect.
Physical Review B **57**, 14818–14828. ISSN: 0163-1829. doi:[10.1103/PhysRevB.57.14818](https://doi.org/10.1103/PhysRevB.57.14818) (1998).
72. Furlan, M.
Activated conductivities and nonuniversal behaviour in large high mobility Hall bars.
Physica B: Condensed Matter **249-251**, 123–127. ISSN: 09214526. doi:[10.1016/S0921-4526\(98\)00081-7](https://doi.org/10.1016/S0921-4526(98)00081-7) (1998).
73. Jeckelmann, B., Jeanneret, B. & Inglis, D.
High-precision measurements of the quantized Hall resistance: Experimental conditions for universality.
Physical Review B - Condensed Matter and Materials Physics **55**, 13124–13134. doi:[10.1103/PhysRevB.55.13124](https://doi.org/10.1103/PhysRevB.55.13124) (1997).
74. Jeanneret, B., Hall, B., Jeckelmann, B., Feller, U., Bühlmann, H.-J. & Ilegems, M.
A.C. measurements of edgeless currents in a Corbino ring in the quantum Hall regime.
Solid State Communications **102**, 287–290. ISSN: 00381098. doi:[10.1016/S0038-1098\(97\)00003-3](https://doi.org/10.1016/S0038-1098(97)00003-3) (1997).
75. Jeanneret, B., Jeckelmann, B., Buhlmann, H.-J. & Begems, M.
Influence of infrared illumination on the accuracy of the quantized Hall resistance.
IEEE Transactions on Instrumentation and Measurement **46**, 285–288. ISSN: 00189456. doi:[10.1109/19.571833](https://doi.org/10.1109/19.571833) (1997).
76. Jeckelmann, B. & Jeanneret, B.
Influence of the voltage contacts on the four-terminal quantized Hall resistance in the non-linear regime.
IEEE Transactions on Instrumentation and Measurement **46**, 276–280. ISSN: 00189456. doi:[10.1109/19.571831](https://doi.org/10.1109/19.571831) (1997).
77. Jeckelmann, B., Inglis, A. D. & Jeanneret, B.
Are anomalous values of the quantized Hall resistance really anomalous?
Metrologia **33**, 499–502. ISSN: 0026-1394. doi:[10.1088/0026-1394/33/5/10](https://doi.org/10.1088/0026-1394/33/5/10) (1996).
78. Jeckelmann, B., Inglis, A. & Jeanneret, B.
Material, Device, and Step Independence of the Quantized Hall Resistance.
IEEE Transactions on Instrumentation and Measurement **44**, 269–272. ISSN: 00189456. doi:[10.1109/19.377828](https://doi.org/10.1109/19.377828) (1995).
79. Jeckelmann, B., Fasel, W. & Jeanneret, B.
Improvements in the realization of the quantized Hall resistance standard at OFMET.
IEEE Transactions on Instrumentation and Measurement **44**, 265–268. ISSN: 00189456. doi:[10.1109/19.377827](https://doi.org/10.1109/19.377827) (1995).

80. Jeanneret, B., Jeckelmann, B., Buhlmann, H.-J., Houdre, R. & Ilegems, M.
Influence of the device-width on the accuracy of quantization in the integer quantum Hall effect.
IEEE Transactions on Instrumentation and Measurement **44**, 254–257. ISSN: 00189456. doi:[10.1109/19.377824](https://doi.org/10.1109/19.377824) (1995).
81. Jeanneret, B., Hall, B. D., Bühlmann, H.-J., Houdré, R., Ilegems, M., Jeckelmann, B. & Feller, U.
Observation of the integer quantum Hall effect by magnetic coupling to a Corbino ring.
Physical Review B **51**, 9752–9756. ISSN: 0163-1829. doi:[10.1103/PhysRevB.51.9752](https://doi.org/10.1103/PhysRevB.51.9752) (1995).
82. Delahaye, F., Witt, T. J., Jeckelmann, B. & Jeanneret, B.
Comparison of quantum Hall effect resistance standards of the OFMET and the BIPM.
Metrologia **32**, 385–388. ISSN: 0026-1394. doi:[10.1088/0026-1394/32/5/6](https://doi.org/10.1088/0026-1394/32/5/6) (1995).
83. Jeckelmann, B., Goudsmit, P. & Leisi, H.
The mass of the negative pion.
Physics Letters B **335**, 326–329. ISSN: 03702693. doi:[10.1016/0370-2693\(94\)90358-1](https://doi.org/10.1016/0370-2693(94)90358-1) (1994).
84. Reyman, D., Feller, U., de la Court, P. & Witt, T. J.
Comparisons of the Josephson Voltage Standard of the BIPM with those of the OFM and the NMI.
Metrologia **31**, 45–48. ISSN: 0026-1394. doi:[10.1088/0026-1394/31/1/009](https://doi.org/10.1088/0026-1394/31/1/009) (1994).
85. Jeckelmann, B., Schwitz, W., Buhlmann, H.-J., Houldre, R., Hegems, M., Jucknischke, D. & Py, M.
Comparison of the quantized hall resistance in different GaAs/Al_xGa_{1-x}/As heterostructures.
IEEE Transactions on Instrumentation and Measurement **40**, 231–233. ISSN: 0018-9456. doi:[10.1109/TIM.1990.1032924](https://doi.org/10.1109/TIM.1990.1032924) (1991).
86. Jucknischke, D., Buhlmann, H., Houdre, R., Ilegems, M., Py, M., Jeckelmann, B. & Schwitz, W.
Properties of alloyed AuGeNi-contacts on GaAs/Ga/AlAs heterostructures.
IEEE Transactions on Instrumentation and Measurement **40**, 228–230. ISSN: 0018-9456. doi:[10.1109/TIM.1990.1032923](https://doi.org/10.1109/TIM.1990.1032923) (1991).
87. Schwitz, W., Bauder, L., Buhlmann, H.-J., Py, M. A. & Ilegems, M.
The quantum Hall effect as a standard to define the laboratory unit of resistance.
IEEE Transactions on Instrumentation and Measurement **IM-36**, 240–244. ISSN: 0018-9456. doi:[10.1109/TIM.1987.6312677](https://doi.org/10.1109/TIM.1987.6312677) (1987).

Conference

1. Corminboeuf, D. **Calibration of the Absolute Linearity of Lock-in Amplifiers.** in *2018 Conference on Precision Electromagnetic Measurements (CPEM 2018)* (IEEE, 2018), 1–2. ISBN: 978-1-5386-0974-3. doi:[10.1109/CPEM.2018.8501155](https://doi.org/10.1109/CPEM.2018.8501155).
2. Thodkar, K., Schonenberger, C., Calame, M., Luond, F., Overney, F. & Jeanneret, B. **Observation of High Accuracy Resistance Quantization in CVD Graphene.** in *2018 Conference on Precision Electromagnetic Measurements (CPEM 2018)* (IEEE, 2018), 1–2. ISBN: 978-1-5386-0974-3. doi:[10.1109/CPEM.2018.8500820](https://doi.org/10.1109/CPEM.2018.8500820).
3. Overney, F., Flowers-Jacobs, N. E., Jeanneret, B., Rufenach, A., Fox, A. E., Dresselhaus, P. D. & Benz, S. P. **Characterization of a Dual Josephson Impedance Bridge.** in *2018 Conference on Precision Electromagnetic Measurements (CPEM 2018)* (IEEE, 2018), 1–2. ISBN: 978-1-5386-0974-3. doi:[10.1109/CPEM.2018.8501035](https://doi.org/10.1109/CPEM.2018.8501035).
4. Schurr, J., Fletcher, N., Gournay, P., Thevenot, O., Overney, F., Johnson, L., Xie, R. & Dierikx, E. **Supplementary Comparison EURAMET.EM-S31.** in *2018 Conference on Precision Electromagnetic Measurements (CPEM 2018)* (IEEE, 2018), 1–2. ISBN: 978-1-5386-0974-3. doi:[10.1109/CPEM.2018.8501090](https://doi.org/10.1109/CPEM.2018.8501090).
5. Estrada, A. H. P. & Overney, F. **Frequency Dependence Evaluation of CENAM Calculable Resistors.** in *2018 Conference on Precision Electromagnetic Measurements (CPEM 2018)* (IEEE, 2018), 1–2. ISBN: 978-1-5386-0974-3. doi:[10.1109/CPEM.2018.8500922](https://doi.org/10.1109/CPEM.2018.8500922).
6. Agustoni, M. & Mortara, A. **A calibration setup for IEC 61850-9-2 test sets.** in *2016 Conference on Precision Electromagnetic Measurements (CPEM 2016)* (IEEE, 2016), 1–2. ISBN: 978-1-4673-9134-4. doi:[10.1109/CPEM.2016.7540644](https://doi.org/10.1109/CPEM.2016.7540644).

7. Eichenberger, A. L., Baumann, H., Jeckelmann, B., Reber, D. & Tommasini, D. **The METAS watt balance Mark II**. in *2016 Conference on Precision Electromagnetic Measurements (CPEM 2016)* (IEEE, **2016**), 1–2. ISBN: 978-1-4673-9134-4. doi:[10.1109/CPEM.2016.7540537](https://doi.org/10.1109/CPEM.2016.7540537).
8. Overney, F. & Jeanneret, B. **Calibration of a LCR-meter at arbitrary phase angles using a fully automated impedance simulator**. in *2016 Conference on Precision Electromagnetic Measurements (CPEM 2016)* (IEEE, **2016**). ISBN: 978-1-4673-9134-4. doi:[10.1109/CPEM.2016.7540610](https://doi.org/10.1109/CPEM.2016.7540610).
9. Jeanneret, B., Overney, F., Scherly, C. & Schaller, G. **Josephson-based characterization of analog-to-digital converters using an equivalent time sampling method**. in *2016 Conference on Precision Electromagnetic Measurements (CPEM 2016)* (IEEE, **2016**), 1–2. ISBN: 978-1-4673-9134-4. doi:[10.1109/CPEM.2016.7540767](https://doi.org/10.1109/CPEM.2016.7540767).
10. Luond, F., Overney, F., Jeanneret, B., Muller, A., Kruskopf, M. & Pierz, K. **AC quantum Hall effect in epitaxial graphene**. in *2016 Conference on Precision Electromagnetic Measurements (CPEM 2016)* (IEEE, **2016**), 1–2. ISBN: 978-1-4673-9134-4. doi:[10.1109/CPEM.2016.7540655](https://doi.org/10.1109/CPEM.2016.7540655).
11. Thodkar, K., Schonenberger, C., Calame, M., Luond, F., Overney, F. & Jeanneret, B. **Characterization of HMDS treated CVD graphene**. in *2016 Conference on Precision Electromagnetic Measurements (CPEM 2016)* (IEEE, **2016**), 1–2. ISBN: 978-1-4673-9134-4. doi:[10.1109/CPEM.2016.7540498](https://doi.org/10.1109/CPEM.2016.7540498).
12. Corminboeuf, D. **Calibration of bridge standard for strain gauge bridge amplifier**. in *17th International Congress of Metrology* (ed Larquier, B.) (EDP Sciences, Les Ulis, France, **2015**), 04004. ISBN: 978-2-7598-1866-2. doi:[10.1051/metrology/201504004](https://doi.org/10.1051/metrology/201504004).
13. Eichenberger, A. L., Baumann, H., Cosandier, F., Jeckelmann, B., Clavel, R., Genoud, D., Reber, D. & Tommasini, D. **The METAS watt balance Mark II experiment: Progress report**. in *29th Conference on Precision Electromagnetic Measurements (CPEM 2014)* (IEEE, **2014**), 714–715. ISBN: 978-1-4799-2479-0. doi:[10.1109/CPEM.2014.6898585](https://doi.org/10.1109/CPEM.2014.6898585).
14. Overney, F., Luond, F. & Jeanneret, B. **Digitally assisted coaxial bridge for automatic quantum Hall effect measurements at audio frequencies**. in *29th Conference on Precision Electromagnetic Measurements (CPEM 2014)* (IEEE, **2014**), 226–227. ISBN: 978-1-4799-2479-0. doi:[10.1109/CPEM.2014.6898341](https://doi.org/10.1109/CPEM.2014.6898341).
15. Overney, F. & Jeanneret, B. **Impedance simulator for automatic calibration of LCR-meters**. in *29th Conference on Precision Electromagnetic Measurements (CPEM 2014)* (IEEE, **2014**), 86–87. ISBN: 978-1-4799-2479-0. doi:[10.1109/CPEM.2014.6898271](https://doi.org/10.1109/CPEM.2014.6898271).
16. Thodkar, K., Nef, C., Fu, W., Schonenberger, C., Calame, M., Luond, F., Overney, F. & Jeanneret, B. **CVD graphene for electrical quantum metrology**. in *29th Conference on Precision Electromagnetic Measurements (CPEM 2014)* (IEEE, **2014**), 540–541. ISBN: 978-1-4799-2479-0. doi:[10.1109/CPEM.2014.6898498](https://doi.org/10.1109/CPEM.2014.6898498).
17. Kohlmann, J., Behr, R., Kieler, O., De Aguilar Rois, J. D., Sira, M., Sosso, A., Trinchera, B., Gran, J., Malmbeek, H., Jeanneret, B., Overney, F., Nissila, J., Lehtonen, T., Ireland, J., Williams, J., Lapuh, R., Voljc, B., Bergsten, T., Eklund, G., Ozturk, T. C., Houtzager, E., van den Brom, H. & Ohlckers, P. **A quantum standard for sampled electrical measurements - main goals and first results of the EMRP project Q-WAVE**. in *29th Conference on Precision Electromagnetic Measurements (CPEM 2014)* (IEEE, **2014**), 522–523. ISBN: 978-1-4799-2479-0. doi:[10.1109/CPEM.2014.6898489](https://doi.org/10.1109/CPEM.2014.6898489).
18. Nissila, J., Ojasalo, K., Kampik, M., Kaasalainen, J., Maisi, V., Casserly, M., Overney, F., Christensen, A., Callegaro, L., D'Elia, V., Tran, N. T. M., Pourdanesh, F., Ortolano, M., Kim, D. B., Penttila, J. & Roschier, L. **A precise two-channel digitally synthesized AC voltage source for impedance metrology**. in *29th Conference on Precision Electromagnetic Measurements (CPEM 2014)* (IEEE, **2014**), 768–769. ISBN: 978-1-4799-2479-0. doi:[10.1109/CPEM.2014.6898612](https://doi.org/10.1109/CPEM.2014.6898612).
19. Zhao, D., Rietveld, G., Braun, J.-P., Overney, F., Lippert, T. & Christensen, A. **Traceable measurement of the electrical parameters of solid-state lighting products**. in *29th Conference on Precision Electromagnetic Measurements (CPEM 2014)* (IEEE, **2014**), 650–651. ISBN: 978-1-4799-2479-0. doi:[10.1109/CPEM.2014.6898553](https://doi.org/10.1109/CPEM.2014.6898553).
20. Ahlers, F., Kucera, J., Poirier, W., Jeanneret, B., Satrapinski, A., Tzalenchuk, A., Vrabcek, P., Bergsten, T., Hwang, C., Yakimova, R. & Kubatkin, S. **The EMRP project GraphOhm - Towards quantum resistance metrology based on graphene**. in *29th Conference on Precision Electromagnetic Measurements (CPEM 2014)* (IEEE, **2014**), 548–549. ISBN: 978-1-4799-2479-0. doi:[10.1109/CPEM.2014.6898502](https://doi.org/10.1109/CPEM.2014.6898502).
21. Overney, F. & Jeanneret, B. **Impedance Simulator for Automatic Calibration of LCR Meters: Proof-of-Principle Experiment**. in *imeko.org* (**2013**), 156–160. ISBN: 9788461654383.

22. Palafox, L., Raso, F., Ku, J., Overney, F., Callegaro, L., Gournay, P., Zio, A., Nissilä, J., Eklund, G. & Lippert, T. **AIM QuTE : Automated Impedance Metrology extending the Quantum Toolbox for Electricity**. in *16th International Congress of Metrology 11001 (2013)*, 11001–p.1–3. doi:[10.1051/metrology/201311001](https://doi.org/10.1051/metrology/201311001).
23. Eichenberger, A., Baumann, H., Jeckelmann, B., Tommasini, D., Cosandier, F., Clavel, R., Beguin, C. & Reber, D. **The METAS watt balance Mark II experiment**. in *2012 Conference on Precision electromagnetic Measurements (IEEE, 2012)*, 426–427. ISBN: 978-1-4673-0442-9. doi:[10.1109/CPEM.2012.6250985](https://doi.org/10.1109/CPEM.2012.6250985).
24. Jeanneret, B., Overney, F., Rufenacht, A. & Mortara, A. **A high voltage josephson-voltage-standard-locked synthesizer**. in *2012 Conference on Precision electromagnetic Measurements (IEEE, 2012)*, 670–671. ISBN: 978-1-4673-0442-9. doi:[10.1109/CPEM.2012.6251107](https://doi.org/10.1109/CPEM.2012.6251107).
25. Overney, F. & Jeanneret, B. **Impedance simulator for automatic calibration of LCR meters over the entire complex plan**. in *2012 Conference on Precision electromagnetic Measurements (IEEE, 2012)*, 684–685. ISBN: 978-1-4673-0442-9. doi:[10.1109/CPEM.2012.6251114](https://doi.org/10.1109/CPEM.2012.6251114).
26. Eichenberger, A. L., Baumann, H., Jeanneret, B. & Jeckelmann, B. **Results from the METAS watt balance**. in *CPEM 2010 (IEEE, 2010)*, 105–106. ISBN: 978-1-4244-6795-2. doi:[10.1109/CPEM.2010.5544254](https://doi.org/10.1109/CPEM.2010.5544254).
27. Jeanneret, B., Overney, F., Rufenacht, A. & Nissila, J. **Transition shape effect in the transients generated by a Programmable Josephson Voltage Standard**. in *CPEM 2010 (IEEE, 2010)*, 54–55. ISBN: 978-1-4244-6795-2. doi:[10.1109/CPEM.2010.5544163](https://doi.org/10.1109/CPEM.2010.5544163).
28. Overney, F. & Jeanneret, B. **Sampling based RLC bridge**. in *CPEM 2010 (IEEE, 2010)*, 400–401. ISBN: 978-1-4244-6795-2. doi:[10.1109/CPEM.2010.5544367](https://doi.org/10.1109/CPEM.2010.5544367).
29. Overney, F., Corminboeuf, D. & Moll, E. **Coaxial multiplexer for high accuracy capacitance measurements**. in *CPEM 2010 (IEEE, 2010)*, 420–421. ISBN: 978-1-4244-6795-2. doi:[10.1109/CPEM.2010.5545287](https://doi.org/10.1109/CPEM.2010.5545287).
30. Overney, F., Rufenacht, A., Braun, J.-P. & Jeanneret, B. **Josephson-based test bench for ac characterization of analog-to-digital converters**. in *CPEM 2010 (IEEE, 2010)*, 215–216. ISBN: 978-1-4244-6795-2. doi:[10.1109/CPEM.2010.5544779](https://doi.org/10.1109/CPEM.2010.5544779).
31. Rufenacht, A., Jeanneret, B. & Lotkhov, S. V. **Electron counting capacitance standard : Progress report**. in *CPEM 2010 (IEEE, 2010)*, 498–499. ISBN: 978-1-4244-6795-2. doi:[10.1109/CPEM.2010.5543625](https://doi.org/10.1109/CPEM.2010.5543625).
32. Rufenacht, A., Overney, F., Mortara, A. & Jeanneret, B. **Josephson-voltage-standard-locked sine wave synthesizer: Implementation and preliminary results**. in *CPEM 2010 (IEEE, 2010)*, 147–148. ISBN: 978-1-4244-6795-2. doi:[10.1109/CPEM.2010.5544102](https://doi.org/10.1109/CPEM.2010.5544102).
33. Eichenberger, A., Baumann, H., Jeanneret, B. & Jeckelmann, B. **Reproducibility of the metas watt balance**. in *2008 Conference on Precision Electromagnetic Measurements Digest (IEEE, 2008)*, 12–13. ISBN: 978-1-4244-2399-6. doi:[10.1109/CPEM.2008.4574628](https://doi.org/10.1109/CPEM.2008.4574628).
34. Jeanneret, B., Overney, F., Callegaro, L. & Mortara, A. **Josephson voltage standard locked sinewaves synthesizer**. in *2008 Conference on Precision Electromagnetic Measurements Digest (IEEE, 2008)*, 74–75. ISBN: 978-1-4244-2399-6. doi:[10.1109/CPEM.2008.4574659](https://doi.org/10.1109/CPEM.2008.4574659).
35. Overney, F., Jeanneret, B. & Mortara, A. **A synchronous sampling system for high precision AC measurements**. in *2008 Conference on Precision Electromagnetic Measurements Digest (IEEE, 2008)*, 596–597. ISBN: 978-1-4244-2399-6. doi:[10.1109/CPEM.2008.4574920](https://doi.org/10.1109/CPEM.2008.4574920).
36. Overney, F. **Realization of the Henry at METAS**. in *2008 Conference on Precision Electromagnetic Measurements Digest (IEEE, 2008)*, 708–709. ISBN: 978-1-4244-2399-6. doi:[10.1109/CPEM.2008.4574976](https://doi.org/10.1109/CPEM.2008.4574976).
37. Ahlers, F., Jeanneret, B., Melcher, J., Overney, F., Schurr, J. & Wood, B. M. **Compendium for precise ac measurements of the quantized Hall resistance**. in *2008 Conference on Precision Electromagnetic Measurements Digest (IEEE, 2008)*, 492–493. ISBN: 978-1-4244-2399-6. doi:[10.1109/CPEM.2008.4574868](https://doi.org/10.1109/CPEM.2008.4574868).
38. Jeckelmann, B. & Jeanneret, B. **The application of the Josephson and quantum Hall effects in electrical metrology**. in *Proceedings of the International School of Physics "Enrico Fermi" 166 (2007)*, 135–179. ISBN: 9781586037840. doi:[10.3254/978-1-58603-784-0-135](https://doi.org/10.3254/978-1-58603-784-0-135).
39. Overney, F., Jeanneret, B. & Jeckelmann, B. **Realization of the Farad at METAS: Performance of the Automated Four Terminal-Pair Bridge**. in *2006 Conference on Precision Electromagnetic Measurements (CPEM 2006) (2006)*, 478–479.

40. Eichenberger, A., Butty, J., Jeanneret, B., Jeckelmann, B., Joyet, A., Krebs, T. & Richard, P. **A New Magnet Design for the METAS Watt Balance.** in *2004 Conference on Precision Electromagnetic Measurements* (IEEE, **2004**), 56–57. ISBN: 0-7803-8493-8. doi:[10.1109/CPEM.2004.305418](https://doi.org/10.1109/CPEM.2004.305418).
41. Hof, C., Jeanneret, B., Eichenberger, A., Overney, F. & Lotkhov, S. **Progress on the Quantum Capacitance Standard at Metas.** in *2004 Conference on Precision Electromagnetic Measurements* (IEEE, **2004**), 546–547. ISBN: 0-7803-8493-8. doi:[10.1109/CPEM.2004.305354](https://doi.org/10.1109/CPEM.2004.305354).
42. Overney, F., Wood, B., Schurr, J. & Jeanneret, B. **NRC-METAS-PTB Collaboration Part 3: Frequency, Current and Field Dependence in the Quantized Hall and Longitudinal Ac Resistance.** in *2004 Conference on Precision Electromagnetic Measurements* (IEEE, **2004**), 271–272. ISBN: 0-7803-8493-8. doi:[10.1109/CPEM.2004.305568](https://doi.org/10.1109/CPEM.2004.305568).
43. Marullo-Reedtz, G., Cerri, R., Waldmann, W., Streit, J., Immonen, P., Blanc, I., Raso, F., Funck, T., Schumacher, B., Dierikx, E., Nunes, M., Vrabcek, P., Rudohradsky, D., Gunnarsson, O., Jeanneret, B., Jeckelmann, B., Pulfer, T., Turhan, S., Yilmaz, O., Williams, J., Slinde, H., Lind, K., Nicolas, J., Lindic, M., Flouda, I. & Erdos, G. **Comparison Euromet.EM-K8 of DC Voltage Ratio: Results.** in *2004 Conference on Precision Electromagnetic Measurements* (IEEE, **2004**), 252–253. ISBN: 0-7803-8493-8. doi:[10.1109/CPEM.2004.305557](https://doi.org/10.1109/CPEM.2004.305557).
44. Wood, B., Overney, F. & Schurr, J. **NRC-Metas-PTB Collaboration, Part 1: Bridges for AC QHR Measurements.** in *2004 Conference on Precision Electromagnetic Measurements* (IEEE, **2004**), 558–559. ISBN: 0-7803-8493-8. doi:[10.1109/CPEM.2004.305360](https://doi.org/10.1109/CPEM.2004.305360).
45. Jones, R., Wheaton, A., Clarkson, P., Marx, R., Schon, K., Sardi, A., Saracco, O., Giorgi, P., Paglia, G., Varetto, G., Bergman, A., Sandberg, A., Hallstrom, J., Chekurov, Y., Jeanneret, B., Jeckelmann, B., Flueli, M., Gournay, P., Koijmans, C. & Dierikx, E. **Euromet 495 Comparison of High Direct Voltage Measurements up to 100 kV.** in *2004 Conference on Precision Electromagnetic Measurements* (IEEE, **2004**), 254–255. ISBN: 0-7803-8493-8. doi:[10.1109/CPEM.2004.305558](https://doi.org/10.1109/CPEM.2004.305558).
46. Hof, C., Jeanneret, B., Eichenberger, A. & Overney, F. **First steps towards a quantum capacitance standard at METAS.** in *CPEM Digest (Conference on Precision Electromagnetic Measurements)* (**2002**), 128–129.
47. Overney, F., Jeanneret, B. & Jeckelmann, B. **Effects of metallic gates on AC quantum Hall measurements.** in *CPEM Digest (Conference on Precision Electromagnetic Measurements)* (**2002**), 540–541.
48. Beer, W., Eichenberger, A., Jeanneret, B., Jeckelmann, B., Pourzand, A., Richard, P. & Schwarz, J. **The metas watt balance: A summary of progress.** in *CPEM Digest (Conference on Precision Electromagnetic Measurements)* (**2002**), 576–577.
49. Behr, R., Kohlmann, J., Janssen, J., Kleinschmidt, P., Williams, J., Lo-Hive, J.-P., Piquemal, F., Hetland, P., Reymann, D., Eklund, G., Hof, C., Jeanneret, B., Chevtchenko, O., Houtzager, E., Van Den Brom, H., Sosso, A., Andreone, D., Penttila, J. & Helioto, P. **Analysis of different measurement set-ups for a programmable Josephson voltage standard.** in *Conference Digest Conference on Precision Electromagnetic Measurements* (IEEE, **2002**), 390–391. ISBN: 0-7803-7242-5. doi:[10.1109/CPEM.2002.1034886](https://doi.org/10.1109/CPEM.2002.1034886).
50. Melcher, J., Schurr, J., Pierz, K., Williams, J., Giblin, S., Cabiati, F., Callegaro, L., Marullo, G., Cassiogo, C., Jeckelmann, B., Lobo, M. & Godinho, I. **The European ACQHE project: Modular system for the calibration of capacitance standards based on the quantum Hall effect.** in *CPEM Digest (Conference on Precision Electromagnetic Measurements)* (**2002**), 250–251.
51. Beer, W., Eichenberger, A.-L., Jeanneret, B., Jeckelmann, B., Pourzand, A., Richard, P., Schneiter, H. & Schwarz, J. **The Swiss Watt Balance: First measurements.** in *17th IMEKO TC3 Conference on Force, Mass and Torque 2001* (**2001**), 260–267. ISBN: 9781634391818.
52. Jeckelmann, B. **The quantum Hall effect and its application in metrology.** in *Proceedings of the International School of Physics "Enrico Fermi"* (**2001**), 263–290.
53. Jeckelmann, B., Rufenacht, A., Jeanneret, B., Overney, F., Pierz, K., von Campenhausen, A. & Hein, G. **European ac QHE project: Summary of the OFMET dc measurements.** in *Conference on Precision Electromagnetic Measurements. Conference Digest. CPEM 2000 (Cat. No.00CH37031)* (**2000**), 521–522.
54. Jeanneret, B., Rufenacht, A. & Burroughs, C. **Comparison between the SNS and SIS Josephson voltage standards at OFMET.** in *Conference on Precision Electromagnetic Measurements. Conference Digest. CPEM 2000 (Cat. No.00CH37031)* (IEEE, **2000**), 389–390. ISBN: 0-7803-5744-2. doi:[10.1109/CPEM.2000.851039](https://doi.org/10.1109/CPEM.2000.851039).

55. Dudle, G., Overney, F., Prost, L., Springer, T., Dach, R. & Schildknecht, T. **Long term time and frequency transfer by GPS CP over a very long baseline.** in *Conference on Precision Electromagnetic Measurements. Conference Digest. CPEM 2000 (Cat. No.00CH37031)* (2000), 76–77.
56. Overney, F., Jeanneret, B. & Furlan, M. **Highly stable tunable cryogenic capacitor.** in *CPEM Digest (Conference on Precision Electromagnetic Measurements)* (2000), 323–324.
57. Reymann, D., Witt, T., Vrabcek, P., Tang, Y., Hamilton, C., Katkov, A., Mendeleyev, D., Jeanneret, B. & Power, O. **Recent developments in BIPM voltage standard comparisons.** in *Conference on Precision Electromagnetic Measurements. Conference Digest. CPEM 2000 (Cat. No.00CH37031)* (IEEE, 2000), 253–254. ISBN: 0-7803-5744-2. doi:[10.1109/CPEM.2000.850972](https://doi.org/10.1109/CPEM.2000.850972).
58. Dudle, G., Overney, F., Schildknecht, T., Springer, T. & Prost, L. **Transatlantic time and frequency transfer by GPS carrier phase.** in *Proceedings of the Annual IEEE International Frequency Control Symposium 1* (1999), 243–246.
59. Jeanneret, B., Jeckelmann, B. & Hall, B. **Contactless measurements of the internal capacitance of a Corbino ring in the quantum Hall regime.** in *CPEM Digest (Conference on Precision Electromagnetic Measurements)* (1998), 420–421.
60. Overney, F., Schildknecht, T., Beutler, G., Prost, L., Davis, J. & Furlong, J. **Results of geodetic time transfer on an European baseline.** in *CPEM Digest (Conference on Precision Electromagnetic Measurements)* (1998), 326–327.
61. Beer, W., Jeanneret, B., Jeckelmann, B. & Richard, P. **Proposal for a new moving-coil experiment.** in *CPEM Digest (Conference on Precision Electromagnetic Measurements)* (1998), 110–111.
62. Furlan, M. **Divergence of the dielectric function with the delocalization transition of quantized 2D electrons.** in *Helvetica Physica Acta* **71** (1998), 15–16.
63. Furlan, M., Eichenberger, A. L., E., K., Jeanneret, B. & Jeckelmann, B. **Single-electron tunneling devices as a possible dc current standard.** *Helvetica Physica Acta* **71**, 5–6 (1998).
64. Jeanneret, B., Jeckelmann, B., Buhlmann, H.-J. & Ilegems, M. **Influence of infrared illumination on precision measurements of the integer quantum hall effect.** in *CPEM Digest (Conference on Precision Electromagnetic Measurements)* (1996), 250–251.
65. Jeckelmann, B. & Jeanneret, B. **Influence of the contact resistance on precision measurements of the quantum hall effect.** in *CPEM Digest (Conference on Precision Electromagnetic Measurements)* (1996), 157–158.
66. Jeanneret, B., Jeckelmann, B., Buehlmann, H.-J., Houdre, R. & Ilegems, M. **Influence of the device-width on the accuracy of quantization in the integer quantum Hall effect.** in *CPEM Digest (Conference on Precision Electromagnetic Measurements)* (1994), 114–115.
67. Jeckelmann, B., Inglis, A. & Jeanneret, B. **High precision comparison of the quantized Hall resistance of MOSFET and GaAs/AlGaAs heterostructure devices.** in *CPEM Digest (Conference on Precision Electromagnetic Measurements)* (1994), 190–191.
68. Jeckelmann, B., Fasel, W. & Jeanneret, B. **Improvements in the realization of the quantized-Hall resistance standard at OFMET.** in *CPEM Digest (Conference on Precision Electromagnetic Measurements)* (1994), 188–189.

Book's chapter

1. Overney, F. in *VDI-Berichte Nr. 2216* VDI Wissen, 195–206 (VDI Verlag GmbH, Düsseldorf, 2013). ISBN: 978-3-18-092216-4.
2. Jeckelmann, B. & Jeanneret, B. *The Quantum Hall Effect as an Electrical Resistance Standard* 55–131. doi:[10.1007/3-7643-7393-8_3](https://doi.org/10.1007/3-7643-7393-8_3) (Birkhäuser Basel, Basel, 2005).

METinfo

1. Overney, F. & Jeanneret, B. **A state-of-the-art impedance simulator.** *METinfo* **2**, 26–31. ISSN: 1660-4733 (2016).

2. Jeanneret, B., Rufenacht, A. & Overney, F.
The Josephson Locked Synthesizer: a State of the Art Quantum Based AC Voltage Source.
METinfo **18/1**, 4–9 (2011).
3. Overney, F.
Réalisation de l'échelle des inductances à METAS.
METinfo, 10–14. ISSN: 1660-6094 (2010).
4. Overney, F.
Réalisation de l'échelle des capacités à METAS.
METinfo, 4–9. ISSN: 1660-6094 (2007).
5. Furlan, M. & Jeanneret, B.
Ein Elektron kommt selten allein.
OFMET info **6/2**, 3–10 (1999).
6. Jeckelmann, B. & Jeanneret, B.
Application de l'effet Hall quantique à la métrologie.
OFMET info **4/2**, 8–14 (1997).